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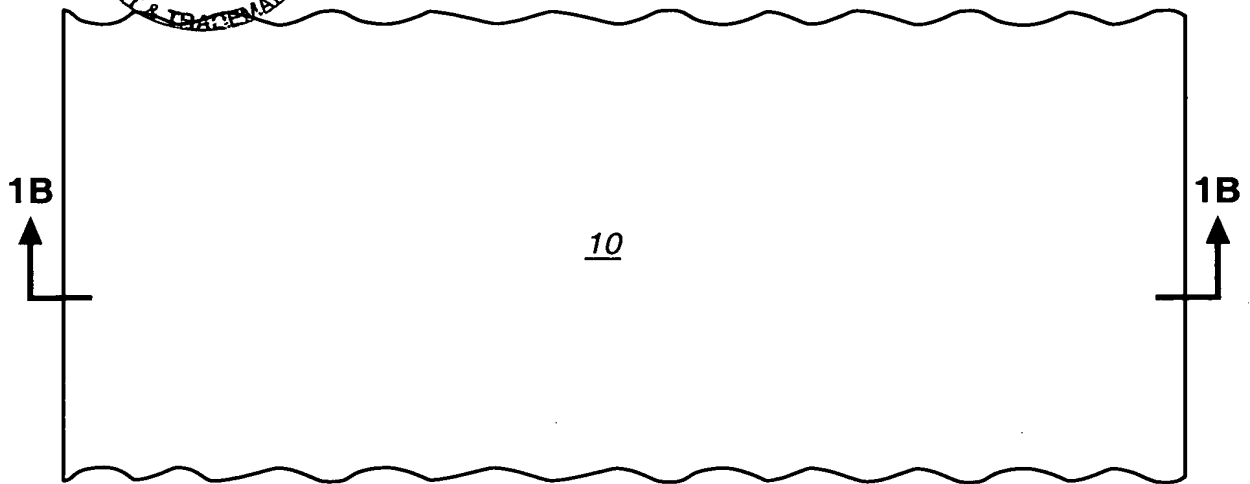


FIG._1A

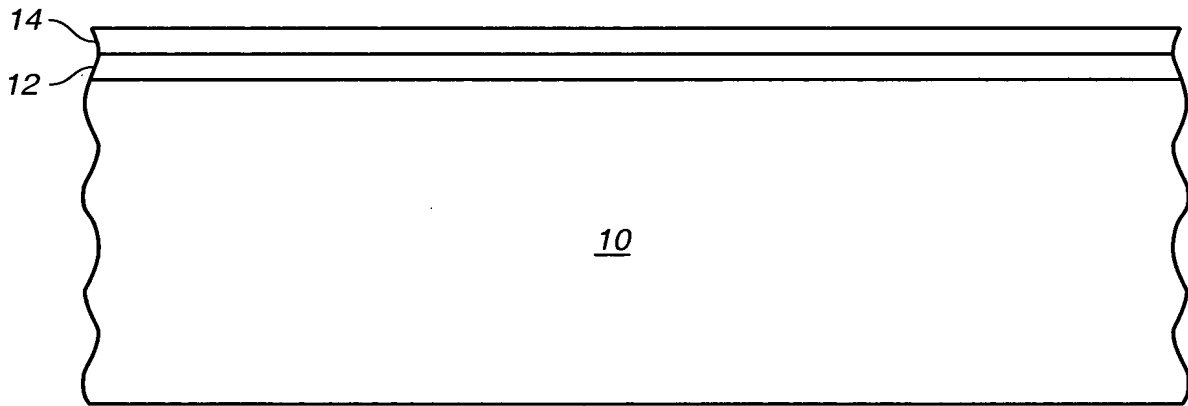


FIG._1B

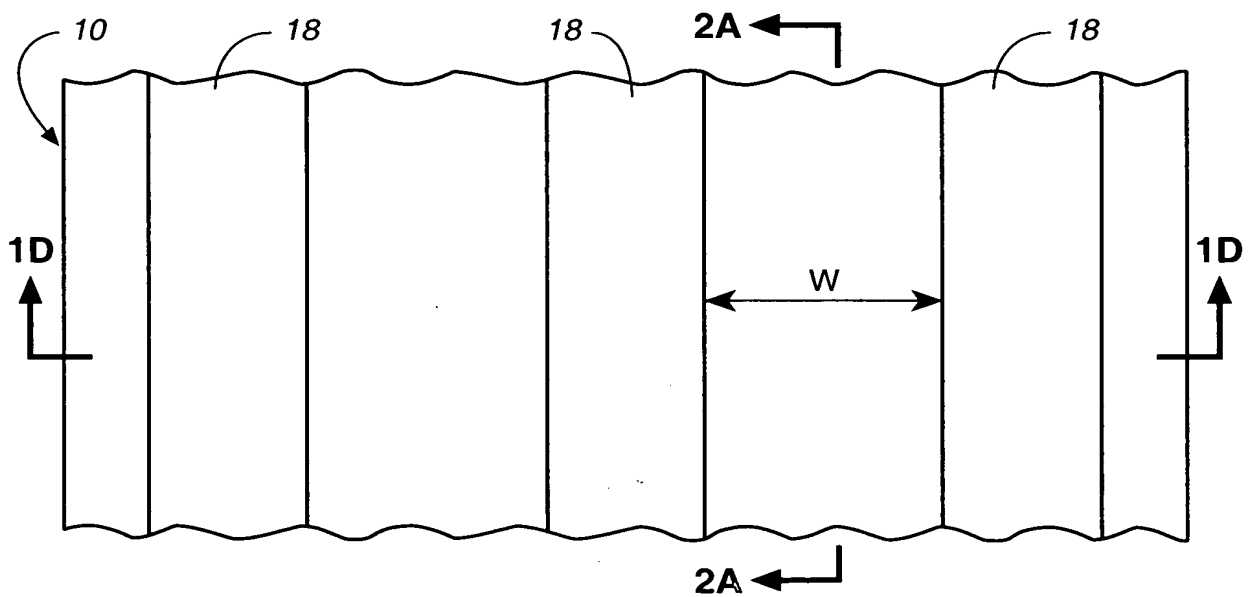


FIG._1C

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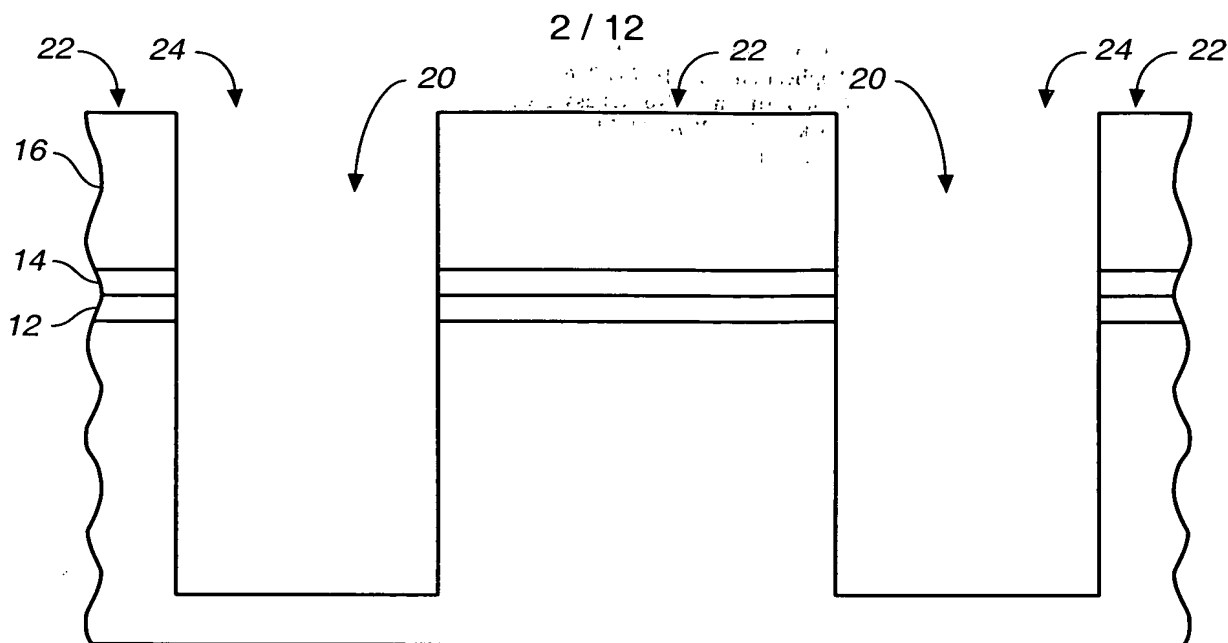


FIG._1D

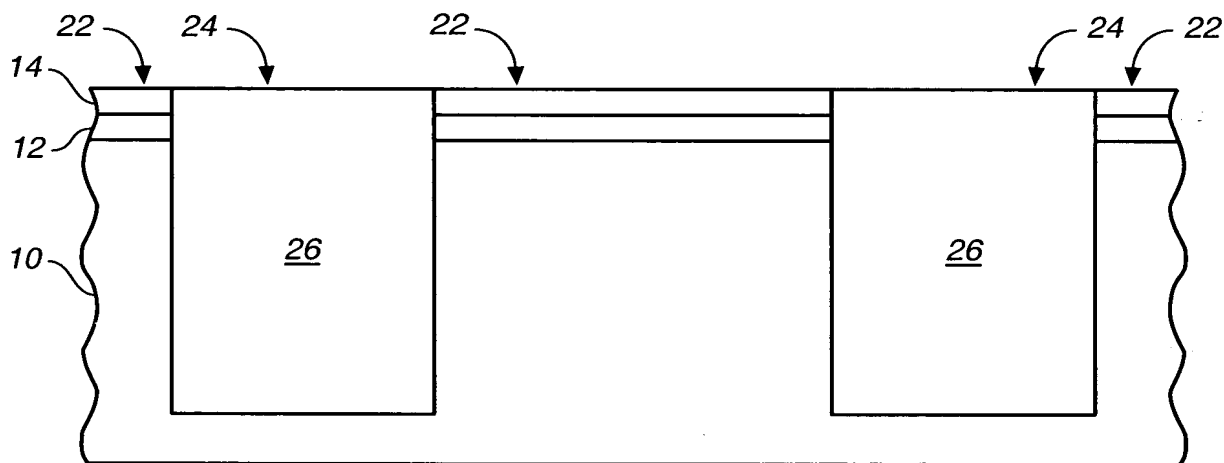


FIG._1E

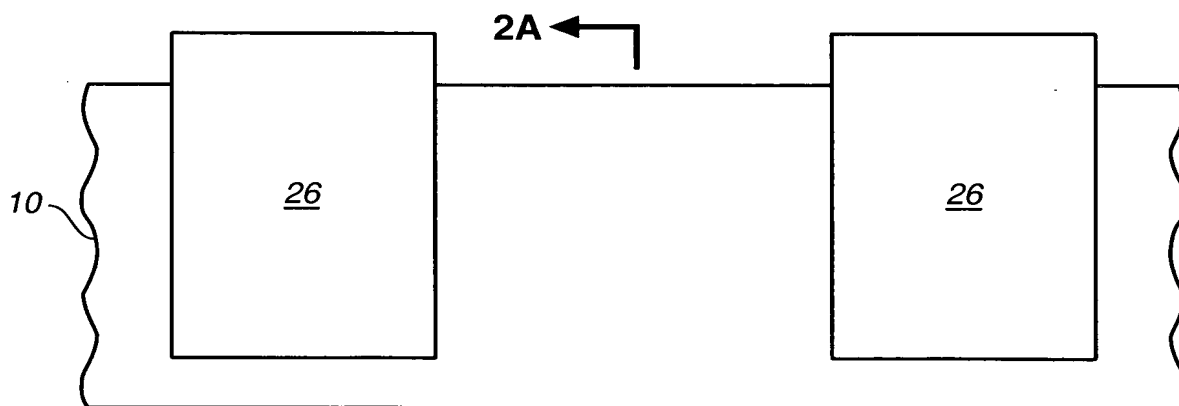


FIG._1F

22

22



10

A cross-sectional view of a semiconductor device 10. It features a substrate with a patterned layer 30 and a textured layer 32. The textured layer 32 is divided into two regions, 34a and 34b, by a gap. The regions 34a and 34b are separated by a gap, and the layer 30 is continuous across the entire structure.

34a

32

30

10

10

34b

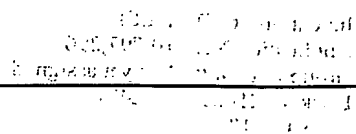
- 32

- 30

FIG. 2B

+





3



+

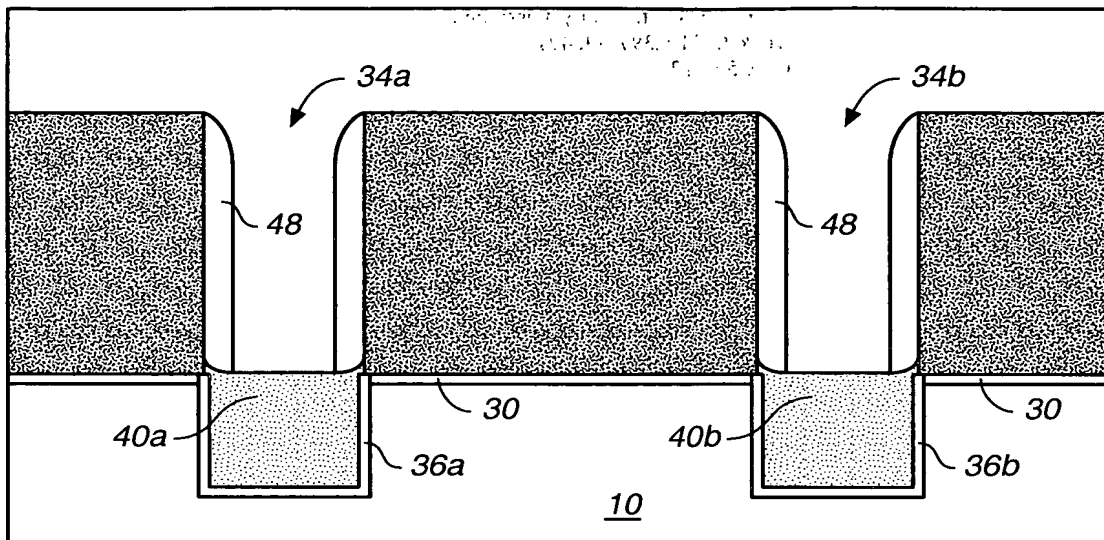


FIG. 2G

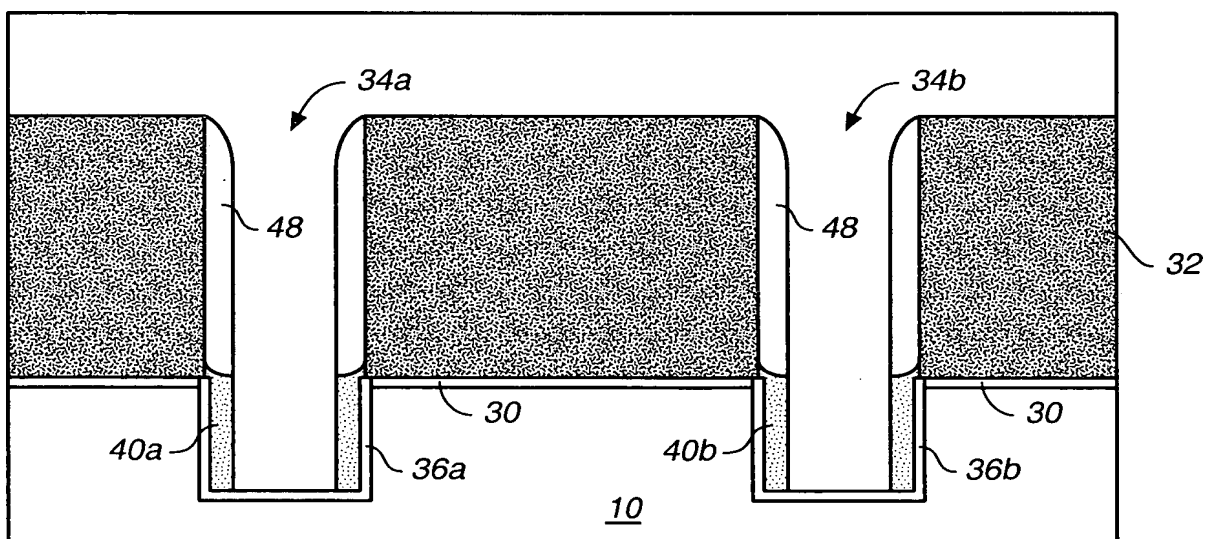


FIG. 2H

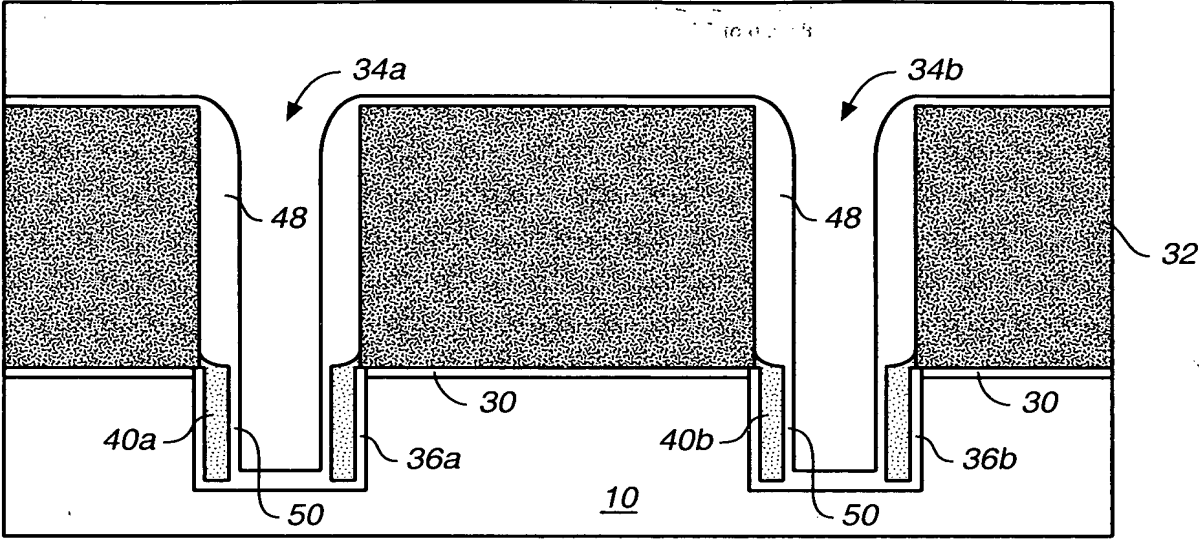


FIG. 2I

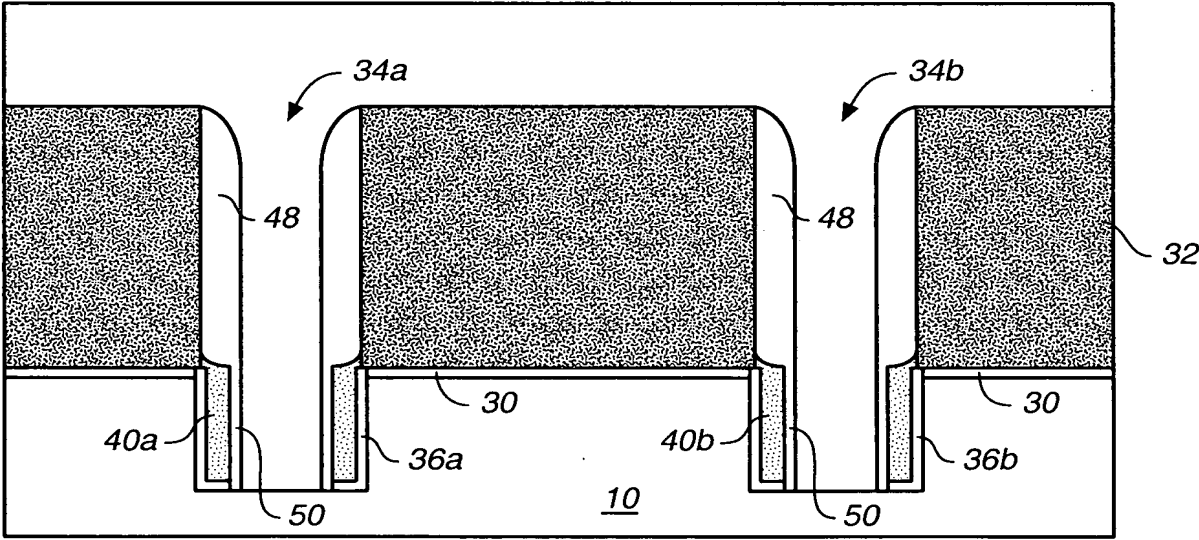
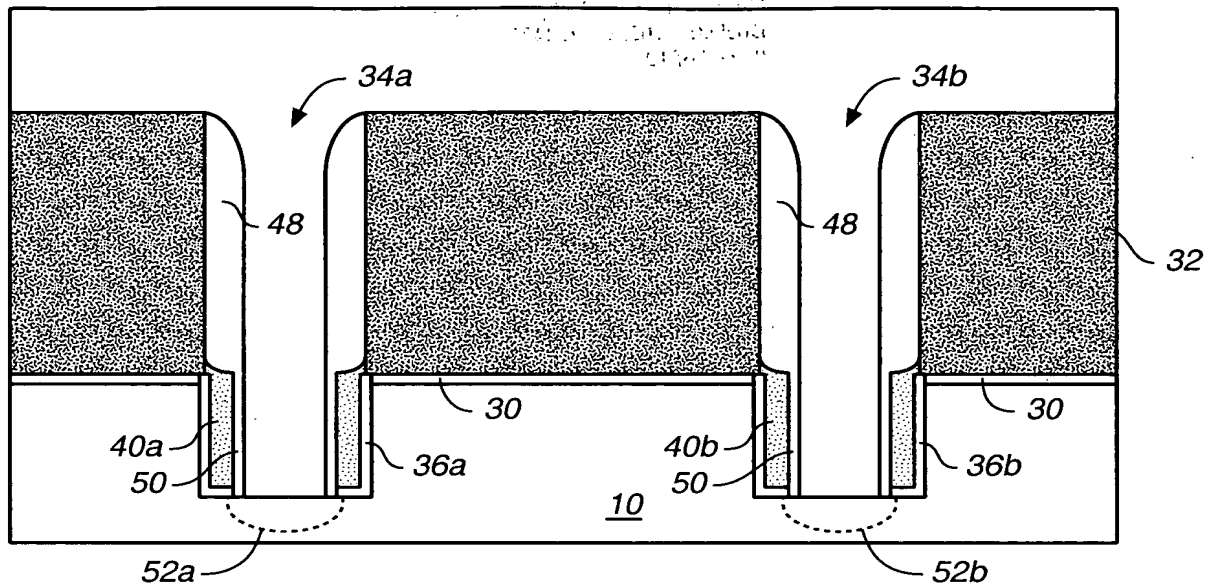
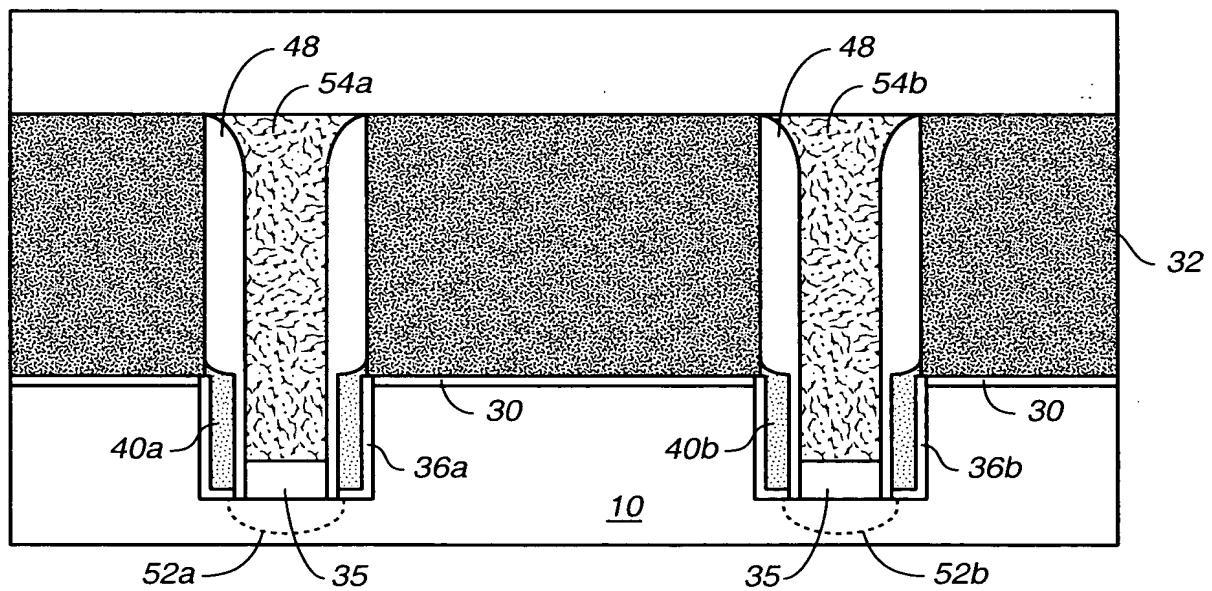


FIG. 2J

**FIG. 2K****FIG. 2L**

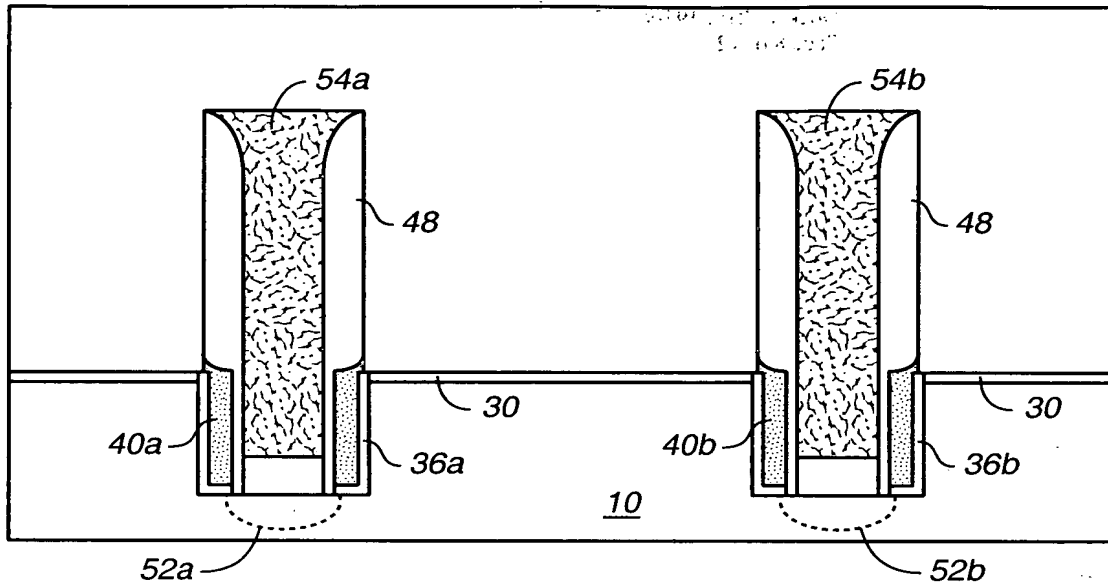


FIG._2M

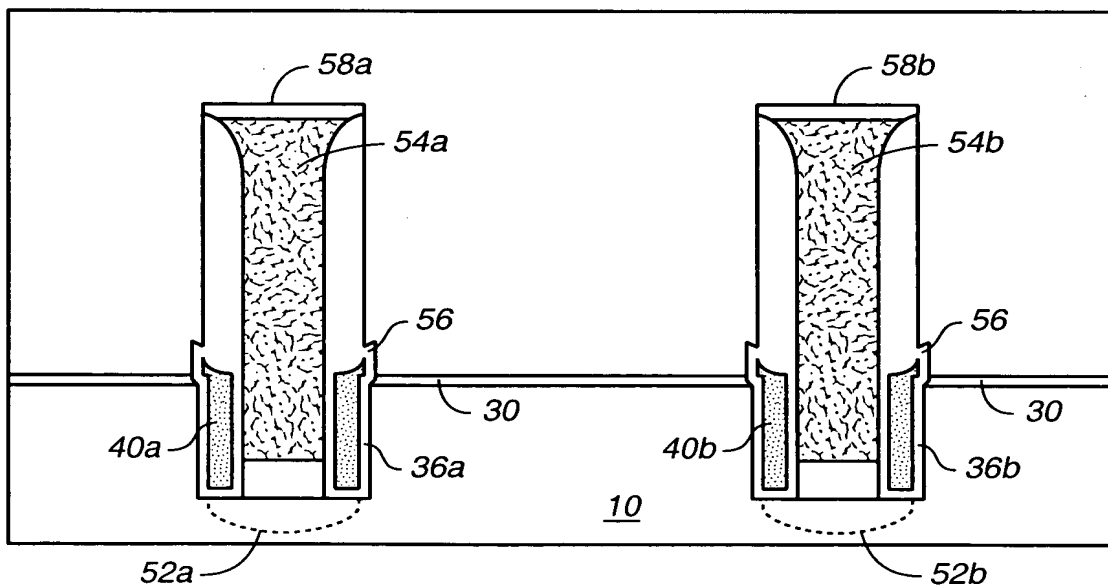


FIG. 2N

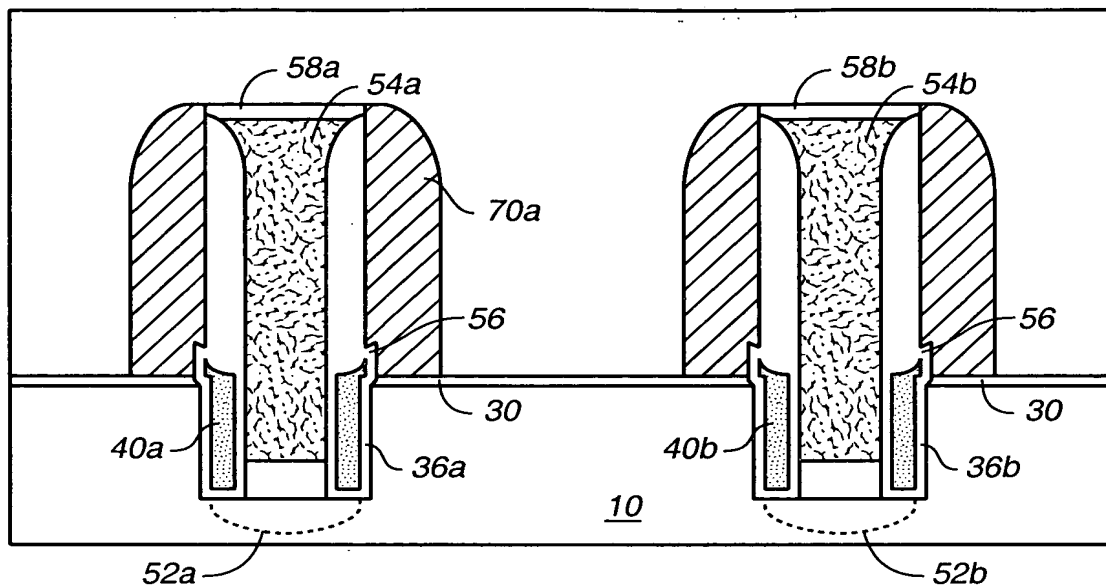


FIG. 20

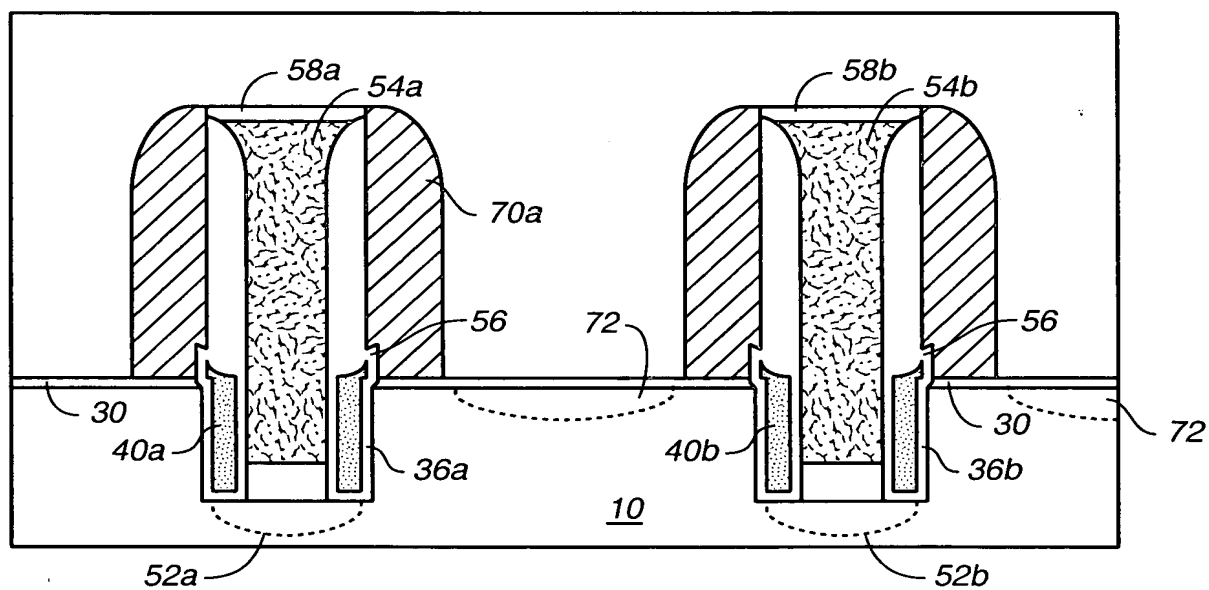
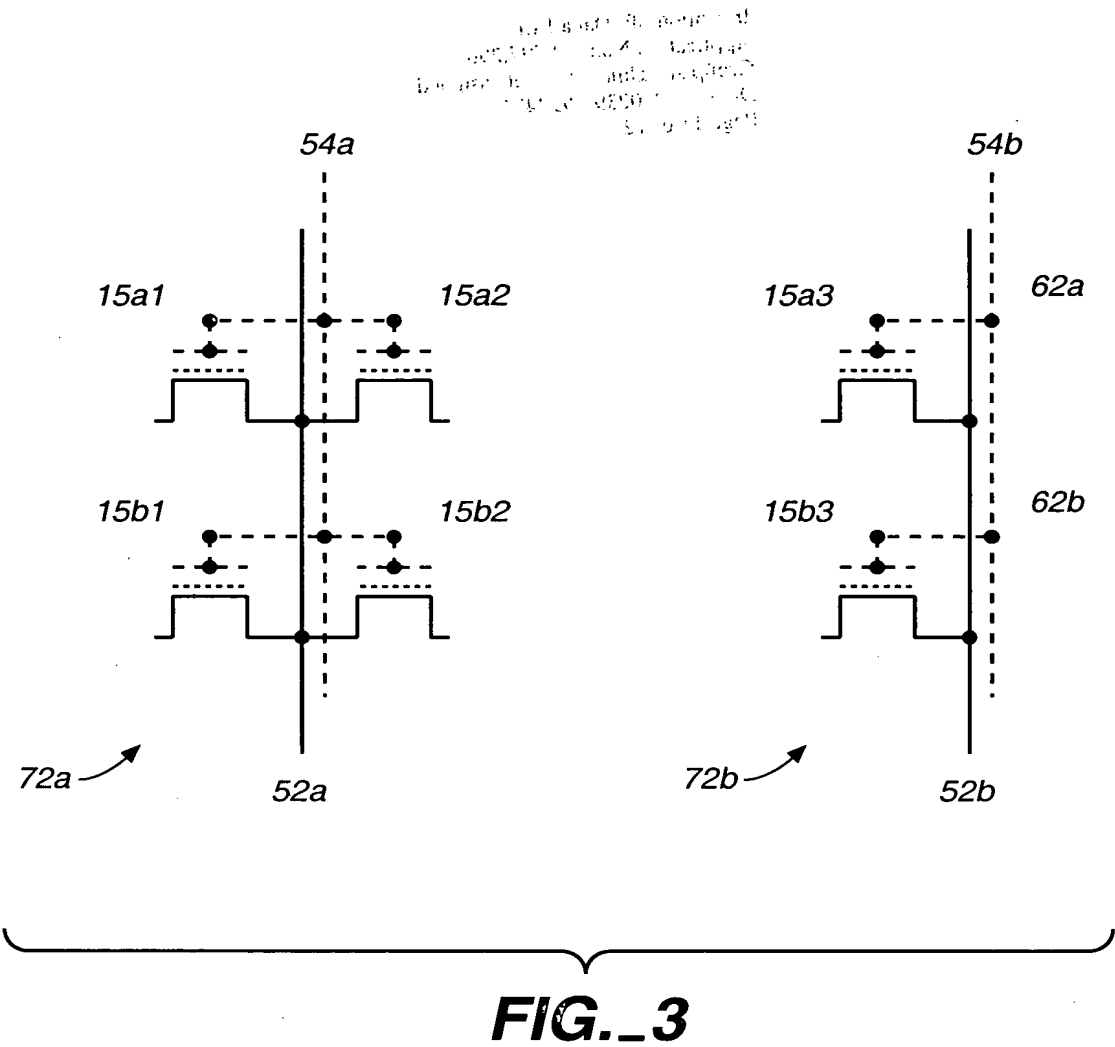


FIG._2P





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